## Search Notes



09464311

Applicant(s)/Patent Under Reexamination

CHEN ET AL.

Examiner

AKIBA K ROBINSON BOYCE

**Art Unit** 

3628

## **SEARCHED**

Class	Subclass	Date	Examiner
705	10	7/27/10	A.R.
705	7	7/27/10	A.R.
705	11	7/27/10	A.R.
			A.R.

SEARCH NOTES	

Search Notes	Date	Examiner
west-((olap) ) and (call adj (patterns or cubes))	7/27/10	A.R.

## **INTERFERENCE SEARCH**

Class	Subclass	Date	Examiner
705	10	7/27/10	A.R.
705	7	7/27/10	A.R.
705	11	7/27/10	A.R.

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